

# **OptiMOS**<sup>TM</sup>3 Power-Transistor

#### **Features**

- · Ideal for high frequency switching
- Optimized technology for DC/DC converters
- Excellent gate charge x R<sub>DS(on)</sub> product (FOM)
- N-channel, normal level
- 100% avalanche tested
- Pb-free plating; RoHS compliant
- Qualified according to JEDEC<sup>1)</sup> for target applications
- Halogen-free according to IEC61249-2-21

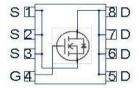
Туре	BSZ340N08NS3 G
Package	PG-TSDSON-8
Marking	340N08N

#### **Product Summary**

V <sub>DS</sub>	80	V
$R_{\mathrm{DS(on),max}}$	34	mΩ
I <sub>D</sub>	23	Α







<b>Waxiiiluiii latiilus.</b> at 1:-25 C. uilless utilei wise specille	less otherwise specified	unless	T = 25 °C	at	ratings.	Maximum
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Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	ID	V <sub>GS</sub> =10 V, T <sub>C</sub> =25 °C	23	А
		V <sub>GS</sub> =10 V, T <sub>C</sub> =100 °C	15	
		V <sub>GS</sub> =10 V, T <sub>A</sub> =25 °C, R <sub>thJA</sub> =60 K/W <sup>2)</sup>	6	
Pulsed drain current <sup>3)</sup>	I <sub>D,pulse</sub>	T <sub>C</sub> =25 °C	92	
Avalanche energy, single pulse <sup>4)</sup>	E <sub>AS</sub>	$I_{\rm D}$ =12 A, $R_{\rm GS}$ =25 Ω	20	mJ
Gate source voltage	$V_{GS}$		±20	V

<sup>1)</sup> J-STD20 and JESD22

<sup>&</sup>lt;sup>2)</sup> Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm2 (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air. <sup>3)</sup> See figure 3 for more detailed information

<sup>&</sup>lt;sup>4)</sup> See figure 13 for more detailed information



## **Maximum ratings,** at $T_i$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Power dissipation	$P_{\text{tot}}$	T <sub>C</sub> =25 °C	32	W
		T <sub>A</sub> =25 °C, R <sub>thJA</sub> =60 K/W <sup>2)</sup>	2.1	
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 150	°C
IEC climatic category; DIN IEC 68-1			55/150/56	

Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	

#### Thermal characteristics

Thermal resistance, junction - case	$R_{\mathrm{thJC}}$		1	-	3.9	K/W
Device on PCB	$R_{\mathrm{thJA}}$	minimal footprint				
		6 cm <sup>2</sup> cooling area <sup>2)</sup>	-	-	60	

## **Electrical characteristics**, at $T_j$ =25 °C, unless otherwise specified

#### Static characteristics

Drain-source breakdown voltage $V_{(B)}$		V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	80	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}=V_{\rm GS}, I_{\rm D}=12~\mu{\rm A}$	2	2.8	3.5	
Zero gate voltage drain current	I <sub>DSS</sub>	$V_{\rm DS} = 80 \text{ V}, \ V_{\rm GS} = 0 \text{ V}, \ T_{\rm j} = 25 \text{ °C}$	1	0.1	5	μA
		V <sub>DS</sub> =80 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	-	10	100	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	-	10	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	V <sub>GS</sub> =10 V, I <sub>D</sub> =12 A	-	27	34	mΩ
		V <sub>GS</sub> =6 V, I <sub>D</sub> =6 A	-	38	66	
Gate resistance	R <sub>G</sub>		-	1	-	Ω
Transconductance	g <sub>fs</sub>	$ V_{\rm DS}  > 2 I_{\rm D} R_{\rm DS(on)max},$ $I_{\rm D} = 12~{\rm A}$	8	16	-	S



Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C <sub>iss</sub>		-	470	630	pF
Output capacitance	Coss	$V_{GS}$ =0 V, $V_{DS}$ =40 V, $f$ =1 MHz	-	130	170	
Reverse transfer capacitance	C <sub>rss</sub>		-	7	-	
Turn-on delay time	$t_{\sf d(on)}$		-	8	-	ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> =40 V, V <sub>GS</sub> =10 V,	-	3	-	
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =12 A, $R_{\rm G,ext}$ =1.6 Ω	-	11	-	1
Fall time	$t_{f}$	]	-	2	-	
Gate Charge Characteristics <sup>5)</sup>					ı	
Gate to source charge	Q <sub>gs</sub>	V <sub>DD</sub> =40 V, I <sub>D</sub> =12 A,	-	2.4	-	nC
Gate charge at threshold	Q <sub>g(th)</sub>		-	1.3	-	
Gate to drain charge	$Q_{gd}$		-	1.5	-	
Switching charge	Q <sub>sw</sub>	V <sub>GS</sub> =0 to 10 V	-	2.6	-	
Gate charge total	Qg		-	6.8	9.1	
Gate plateau voltage	$V_{ m plateau}$		-	5.2	-	V
Output charge	Qoss	$V_{\rm DD}$ =40 V, $V_{\rm GS}$ =0 V	-	9	12	nC
Reverse Diode	•					
Diode continuous forward current	Is	- T <sub>C</sub> =25 °C	-	-	23	А
Diode pulse current	/ <sub>S,pulse</sub>	1 <sub>C</sub> =25 C	-	-	92	
Diode forward voltage	$V_{\mathrm{SD}}$	V <sub>GS</sub> =0 V, I <sub>F</sub> =12 A, T <sub>j</sub> =25 °C	-	0.9	1.2	V
Reverse recovery time	t <sub>rr</sub>	V <sub>R</sub> =40 V, I <sub>F</sub> =12A,	-	43	-	ns
Reverse recovery charge	Qrr	d <i>i</i> <sub>F</sub> /d <i>t</i> =100 A/μs	-	41	-	nC

 $<sup>^{5)}</sup>$  See figure 16 for gate charge parameter definition

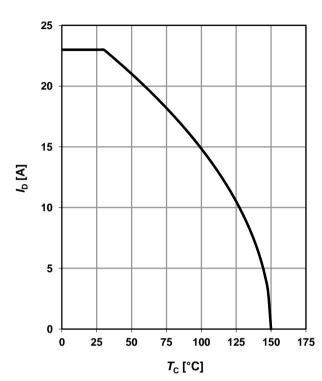


### 1 Power dissipation

## $P_{\text{tot}} = f(T_{\text{C}})$

# 30 30 10 10 0 0 25 50 75 100 125 150 175 T<sub>C</sub> [°C]

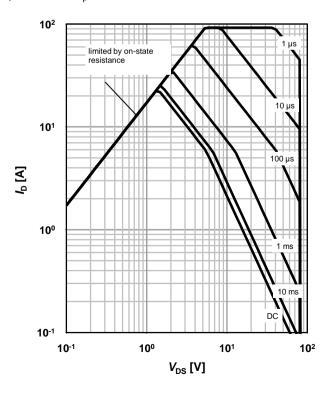
### 2 Drain current



## 3 Safe operating area

 $I_D=f(V_{DS}); T_C=25 \text{ °C}; D=0$ 

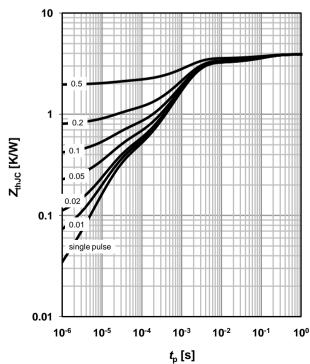
parameter:  $t_p$ 



#### 4 Max. transient thermal impedance

 $Z_{\rm thJC}$ =f $(t_{\rm p})$ 

parameter:  $D=t_p/T$ 

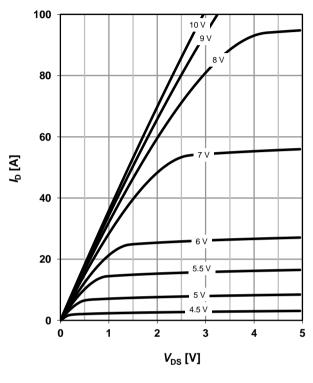




### 5 Typ. output characteristics

 $I_D=f(V_{DS}); T_j=25 °C$ 

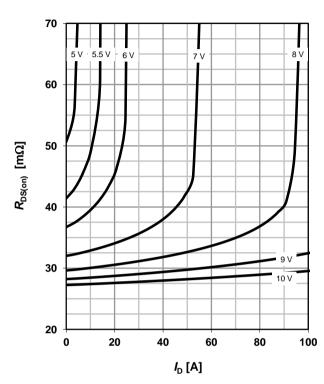
parameter: V<sub>GS</sub>



# 6 Typ. drain-source on resistance

 $R_{DS(on)}=f(I_D); T_j=25 °C$ 

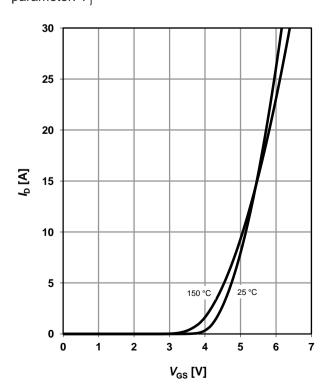
parameter: V<sub>GS</sub>



### 7 Typ. transfer characteristics

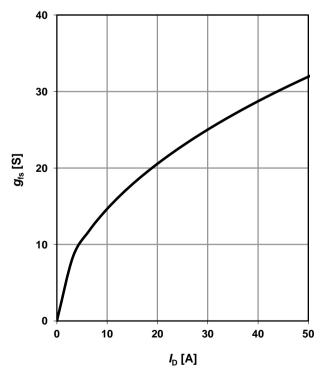
 $I_{D}=f(V_{GS}); |V_{DS}|>2|I_{D}|R_{DS(on)max}$ 

parameter:  $T_{\rm j}$ 



## 8 Typ. forward transconductance

$$g_{fs}$$
=f( $I_D$ );  $T_j$ =25 °C



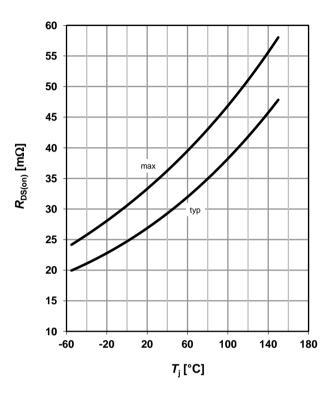


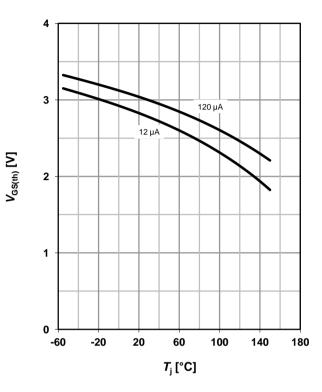
### 9 Drain-source on-state resistance

## $R_{DS(on)} = f(T_i); I_D = 12 \text{ A}; V_{GS} = 10 \text{ V}$

## 10 Typ. gate threshold voltage

$$V_{GS(th)} = f(T_i); V_{GS} = V_{DS}$$





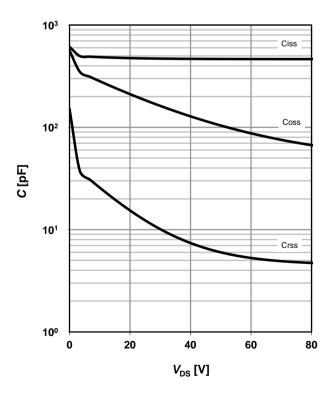
## 11 Typ. capacitances

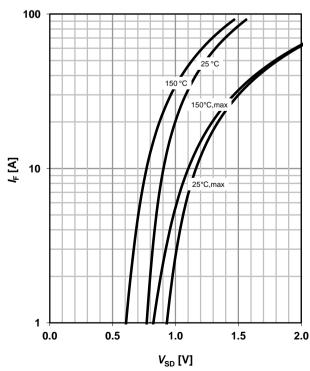
 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz$ 

#### 12 Forward characteristics of reverse diode

 $I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$ 

parameter:  $T_{\rm j}$ 



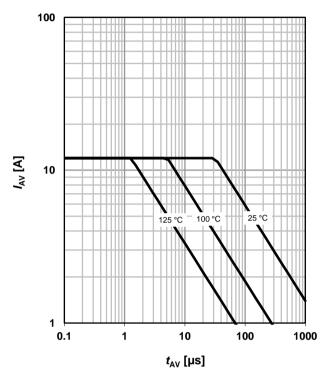




#### 13 Avalanche characteristics

 $I_{AS}=f(t_{AV}); R_{GS}=25 \Omega$ 

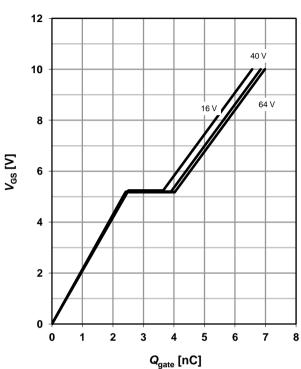
parameter:  $T_{j(start)}$ 



## 14 Typ. gate charge

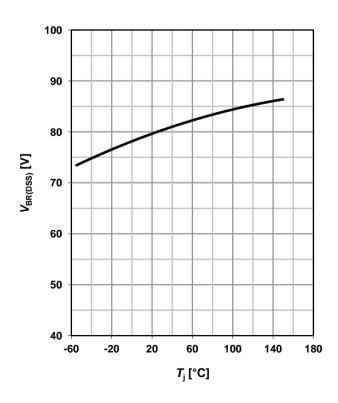
 $V_{GS}$ =f( $Q_{gate}$ );  $I_D$ =12 A pulsed

parameter: V<sub>DD</sub>

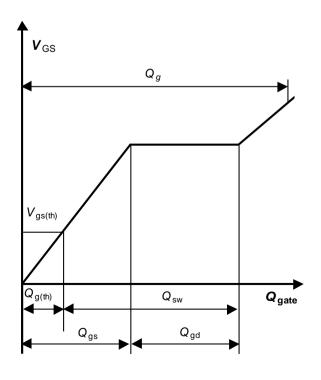


## 15 Drain-source breakdown voltage

 $V_{BR(DSS)}=f(T_j); I_D=1 \text{ mA}$ 

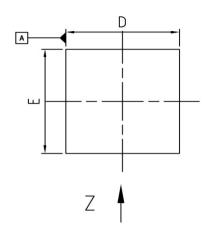


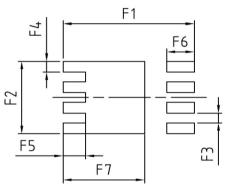
## 16 Gate charge waveforms

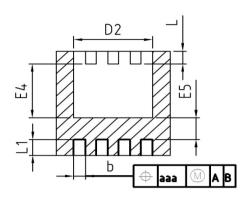


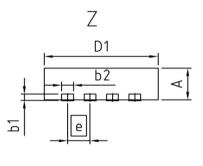


## **PG-TSDSON-8**









DIM	MILLIMETERS INCHES			HES		
DIM	MIN	MAX	MIN	MAX		
Α	0.90	1.10	0.035	0.043		
b	0.24	0.44	0.009	0.017		
ь1	0.10	0.30	0.004	0.012		
ь2	0.20	0.44	0.008	0.017		
D=D1	3.20	3.40	0.126	0.134		
D2	2.15	2.45	0.085	0.096		
E	3.20	3.40	0.126	0.134		
E4	1.60	1.81	0.063	0.071		
E5	0.59	0.86	0.023	0.034		
е	0.0	0.65 0.026		0.65		026
N	8		8			
L	0.30	0.56	0.012	0.022		
L1	0.33	0.60	0.013	0.024		
aaa	0.2	25	0.010			
F1	3.8	30	0.150			
F2	2.29		0.090			
F3	0.31		0.012			
F4	0.34		0.013			
F5	0.65		0.026			
F6	0.80		0.031			
F7	2.3	36	0.0	093		

DOCUMENT NO. Z8B00131645
SCALE 0
2.5 = 0 2.5 = 1 5mm
EUROPEAN PROJECTION
ISSUE DATE 17-09-2008
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